

PowerMOS transistor

BUK438W-800A/B

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic envelope.
The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

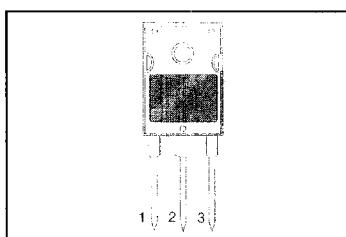
QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	MAX.	UNIT
	BUK438	-800A	-800B	
V_{DS}	Drain-source voltage	800	800	V
I_D	Drain current (DC)	7.6	6.6	A
P_{tot}	Total power dissipation	220	220	W
$R_{DS(ON)}$	Drain-source on-state resistance	1.5	2.0	Ω

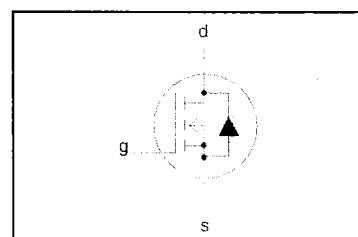
PINNING - SOT429 (TO247)

PIN	DESCRIPTION
1	gate
2	drain
3	source
tab	drain

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.		MAX.		UNIT
			-	-	-	-	
V_{DS}	Drain-source voltage	-			800		V
V_{DGR}	Drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$			800		V
$\pm V_{GS}$	Gate-source voltage	-			30		V
I_D	Drain current (DC)	$T_{mb} = 25^\circ\text{C}$	-	7.6	6.6		A
I_D	Drain current (DC)	$T_{mb} = 100^\circ\text{C}$	-	4.8	4.1		A
I_{DM}	Drain current (pulse peak value)	$T_{mb} = 25^\circ\text{C}$	-	30	26		A
P_{tot}	Total power dissipation	$T_{mb} = 25^\circ\text{C}$	-		220		W
T_{stg}	Storage temperature	-	-55		150		$^\circ\text{C}$
T_J	Junction temperature	-	-		150		$^\circ\text{C}$

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$R_{th(j-mb)}$	Thermal resistance junction to mounting base		-	-	0.57	K/W
$R_{th(j-a)}$	Thermal resistance junction to ambient		-	45	-	K/W

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STATIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT	
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	800	-	-	V	
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V	
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 800 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	-	5	50	μA	
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 800 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA	
I_{GSS}	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA	
$R_{DS(ON)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 4.0 \text{ A}$	BUK438-800A	-	1.2	1.5	Ω
			BUK438-800B	-	1.6	2.0	Ω

DYNAMIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{ls}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 4.0 \text{ A}$	3.0	7.5	-	S
C_{iss}	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	2000	3000	pF
C_{oss}	Output capacitance		-	200	300	pF
C_{rss}	Feedback capacitance		-	100	200	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30 \text{ V}; I_D = 2.6 \text{ A}; V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega; R_{gen} = 50 \Omega$	-	40	90	ns
t_r	Turn-on rise time		-	100	140	ns
$t_{d(off)}$	Turn-off delay time		-	300	430	ns
t_f	Turn-off fall time		-	100	140	ns
L_d	Internal drain inductance	Measured from contact screw on tab to centre of die	-	5	-	nH
L_d	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	5	-	nH
L_s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	12.5	-	nH

REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	7.6	A
I_{DRM}	Pulsed reverse drain current	-	-	-	30	A
V_{SD}	Diode forward voltage	$I_F = 7.6 \text{ A}; V_{GS} = 0 \text{ V}$	-	0.9	1.3	V
t_{rr}	Reverse recovery time	$I_F = 7.6 \text{ A}; -di_F/dt = 100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V}; V_R = 100 \text{ V}$	-	1.5	-	μs
Q_{rr}	Reverse recovery charge		-	20	-	μC

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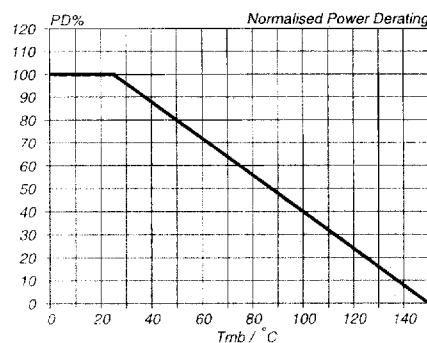


Fig.1. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D,25\text{ }^{\circ}\text{C}} = f(T_{mb})$

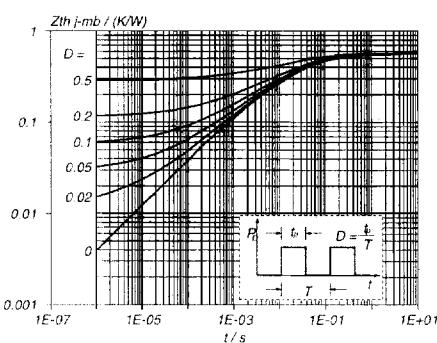


Fig.4. Transient thermal impedance.
 $Z_{th,j-mb} = f(t); \text{parameter } D = t/T$

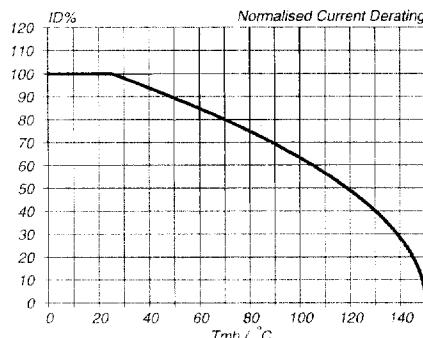


Fig.2. Normalised continuous drain current.
 $ID\% = 100 \cdot I_D / I_{D,25\text{ }^{\circ}\text{C}} = f(T_{mb}); \text{conditions: } V_{GS} \geq 10 \text{ V}$

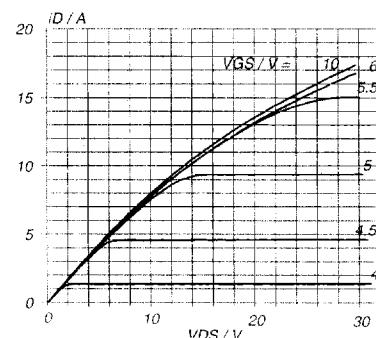


Fig.5. Typical output characteristics, $T_j = 25\text{ }^{\circ}\text{C}$.
 $I_D = f(V_{DS}); \text{parameter } V_{GS}$

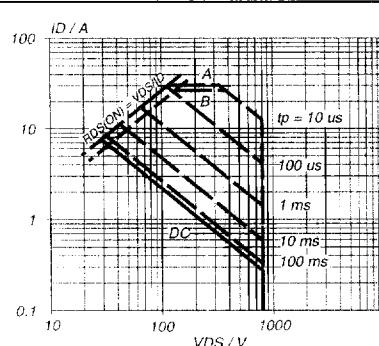


Fig.3. Safe operating area. $T_{mb} = 25\text{ }^{\circ}\text{C}$
 $I_D \& I_{DM} = f(V_{DS}); I_{DM}$ single pulse; parameter t_p

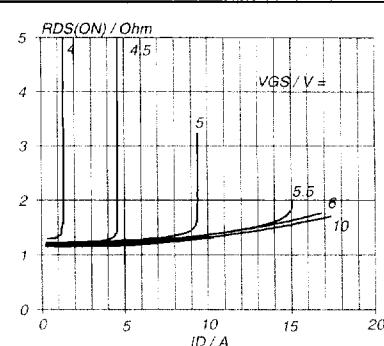


Fig.6. Typical on-state resistance, $T_j = 25\text{ }^{\circ}\text{C}$.
 $R_{DS(ON)} = f(I_D); \text{parameter } V_{GS}$

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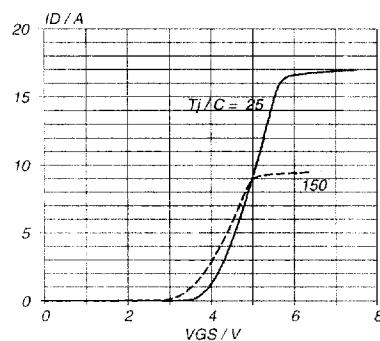


Fig. 7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25$ V; parameter T_j

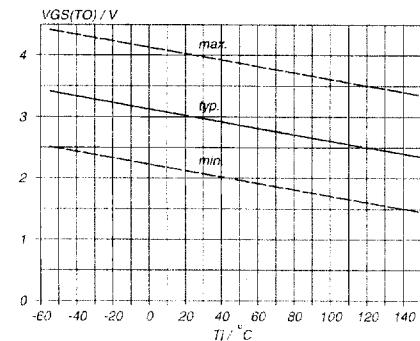


Fig. 10. Gate threshold voltage.
 $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1$ mA; $V_{DS} = V_{GS}$

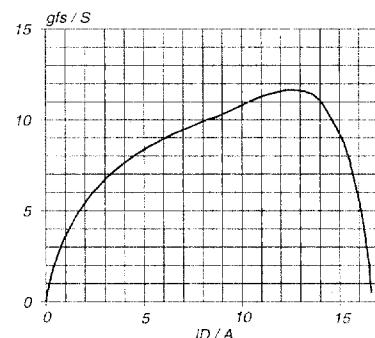


Fig. 8. Typical transconductance, $T_j = 25$ °C.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25$ V

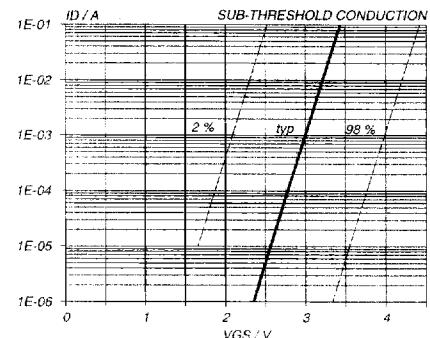


Fig. 11. Sub-threshold drain current.
 $I_D = f(V_{GS})$; conditions: $T_j = 25$ °C; $V_{DS} = V_{GS}$

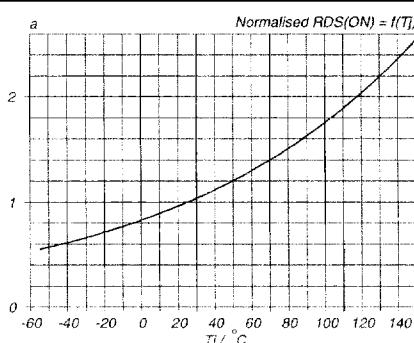


Fig. 9. Normalised drain-source on-state resistance.
 $a = R_{DS(\text{ON})}/R_{DS(\text{ON})25\text{ }{}^\circ C} = f(T_j)$; $I_D = 4$ A; $V_{GS} = 10$ V

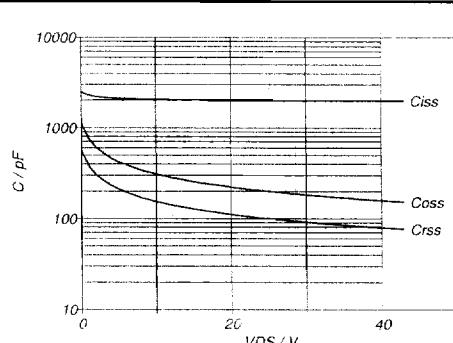


Fig. 12. Typical capacitances, C_{iss} , C_{oss} , C_{rss} .
 $C = f(V_{DS})$; conditions: $V_{GS} = 0$ V; $f = 1$ MHz

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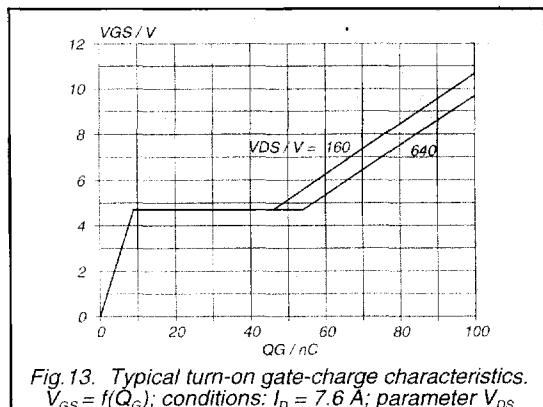


Fig. 13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; conditions: $I_D = 7.6 \text{ A}$; parameter V_{DS}

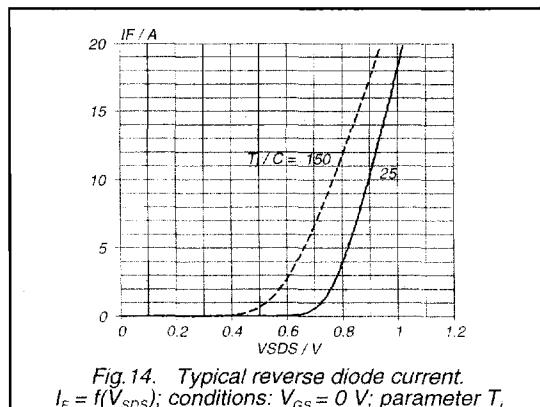


Fig. 14. Typical reverse diode current.
 $I_F = f(V_{SDS})$; conditions: $V_{GS} = 0 \text{ V}$; parameter T_J